

Notice of References Cited	Application/Control No. 10/670,253	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Kimnhung Nguyen	Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0160435	08-2004	Cui et al.	345/211
*	B	US-6,975,324	12-2005	Valmiki et al.	345/555
*	C	US-2002/0101528	08-2002	LEE et al.	348/304
*	D	US-6,661,422	12-2003	Valmiki et al.	345/530
*	E	US-2002/0113762	08-2002	Ha, Yong Min	345/87
*	F	US-7,030,871	04-2006	Kitagawa et al.	345/213
*	G	US-7,061,478	06-2006	Moyer, Todd K.	345/204
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.